

Welcome and Introduction

EUV Source Workshop

Hilton Hotel, Santa Clara

Sierra Ballroom

February 23, 2003

EUV Source Workshop Organization Committee

Vadim Banine – ASML Fred Bijkerk - FOM
Nigel Farrar – Cymer Glen Kubiak - Sandia
Uwe Stamm- MEDEA+ Koichi Toyoda- SUT
Vivek Bakshi (Chair) -ISMT

Presentation Outline

- **Open Conference: Confidentiality Notice**
- **Workshop Purpose**
- **Workshop Agenda**

OPEN Conference: Confidentiality Notice

- **This meeting is an Open Conference**
- **Confidential or proprietary information may NOT be disclosed**
- **Out of courtesy to presenters, photographs and videos are not permitted**
- **Presenters must provide copies of their presentations to International SEMATECH, to be made available on ISMT public web-site, following this meeting**

Workshop Purpose

- **Review source requirements**
- **Review progress in EUV source performance**
- **Review critical challenges and technology developments related to EUV sources**
- **Breakout session to review:**
 - Roadmap for standardized source metrology
 - Fundamental data and modeling requirements and
 - EUV source critical component lifetime issues

Workshop Agenda

8:00 Opening Remarks/Welcome

Vivek Bakshi, *International SEMATECH*

SESSION I - Robert Bristol, Chair

8:05 EUVL Overview

Kevin Kemp, *International SEMATECH*

8:10 EUV Source Overview

Vivek Bakshi, *International SEMATECH*

8:15 Contamination Workshop Highlights

Obert Wood, *International SEMATECH*

8:20 EUV Source Requirements

Vadim Banine, *ASML*

8:40 Cymer presentation

Igor Fomenkov

9:00 EUVA presentation

Akira Endo

9:20 EXULITE presentation

Bernard Fay

9:40 Innolite presentation

Björn Hansson

10:00 BREAK

Workshop Agenda

SESSION II - Stefan Wurm, Chair

10:20 JMAR presentation

10:40 Philips Extreme presentation

11:00 PLEX presentation

11:20 Powerlase presentation

11:40 NGST/CEO presentation

12:00 LUNCH

13:00 Xtreme Technology presentation

SESSION III - Akira Endo, Chair

13:20 EUV Source Metrology Roadmap

13:40 EUV Source Metrology Supplier Update

14:00 EUV Source Fund. Data Requirements

14:20 EUV Source Critical Component Lifetime

14:40 Condenser Optic Lifetime Issues

15:00 BREAK

Edmond Turcu

Joseph Pankert

Malcolm Mcgeoch

Michael Egan

Stuart McNaught

Uwe Stamm

Max Schuermann, *Jenoptik*

Fred Bijkerk, *FOM Institute*

John Gillaspay, *NIST*

Ahmad Hassanein, *Argonne National Lab*

Bill Ballard, *Sandia National Labs*

Workshop Agenda

SESSION IV - Joseph Pankert, Chair

15:20 Parallel Break-out Sessions

EUV Source Metrology

Mendicino Room

Fundamental Data & Modeling Requirements

Big Sur Room

EUV Source Critical Comp. Lifetime

Sierra Ballroom

Max Schuermann/Fred Bijkerk

John Gillaspay/Bryan Rice

Glenn Kubiak/Bill Ballard

16:20 RETURN FROM BREAK-OUT SESSIONS

REPORT OUT:

16:20 EUV Source Metrology

16:30 Fundamental Data & Modeling Requirements

16:40 EUV Source Critical Comp. Lifetime

16:50 Meeting Highlights

Max Schuermann

John Gillaspay

Glenn Kubiak

Vivek Bakshi

SESSION V - Dick Moyer, Chair

17:00 Meeting adjourns to parallel Poster Session & Reception / Social Hour

Hotel Logistics

HILTON SANTA CLARA - MAIN LEVEL

